







SN74LV74A-Q1

SCLS556C - DECEMBER 2003 - REVISED AUGUST 2023

## SN74LV74A-Q1 Automotive Dual Positive-Edge-Triggered D-Type Flip-Flop

#### 1 Features

- Qualified for automotive applications
- Operation of 2-V to 5.5-V  $V_{CC}$
- Max t<sub>pd</sub> of 13 ns at 5 V
- Typical V<sub>OLP</sub> (output ground bounce) <0.8 V at V<sub>CC</sub>  $= 3.3 \text{ V}, T_A = 25^{\circ}\text{C}$
- Typical V<sub>OHV</sub> (output V<sub>OH</sub> undershoot) >2.3 V at  $V_{CC} = 3.3 \text{ V}, T_A = 25^{\circ}\text{C}$
- Support mixed-mode voltage operation on all ports
- I<sub>off</sub> supports partial-power-down mode operation
- Latch-up performance exceeds 250 mA per JESD

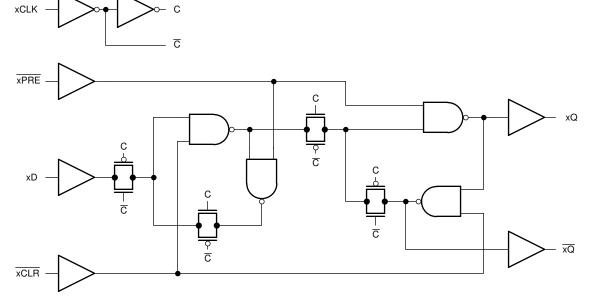
### 2 Description

This dual positive-edge-triggered D-type flip-flop is designed for 2-V to 5.5-V V<sub>CC</sub> operation.

#### **Package Information**

PART NUMBER	PACKAGE <sup>1</sup>	PACKAGE SIZE <sup>2</sup>
SN74LV74A-Q1	PW (TSSOP, 14)	5.00 mm × 6.4 mm
SINTALV TAA-QT	D (SOIC, 14)	8.65 mm x 6 mm

- For all available packages, see the orderable addendum at the end of the data sheet.
- The package size (length × width) is a nominal value and includes pins, where applicable.



Logic Diagram, Each Flip-flop (Positive Logic)



#### **Table of Contents**

1 Features1	5.12 Noise Characteristics
2 Description1	5.13 Operating Characteristics
3 Revision History2	6 Parameter Measurement Information
4 Pin Configuration and Functions3	7 Detailed Description
5 Specifications4	7.1 Overview
5.1 Absolute Maximum Ratings4	7.2 Functional Block Diagram
5.2 ESD Ratings4	7.3 Device Functional Modes
5.3 Recommended Operating Conditions4	8 Device and Documentation Support10
5.4 Thermal Information5	8.1 Documentation Support10
5.5 Electrical Characteristics5	8.2 Receiving Notification of Documentation Updates10
5.6 Timing Requirements, V <sub>CC</sub> = 2.5 V ±0.2 V5	8.3 Support Resources10
5.7 Timing Requirements, V <sub>CC</sub> = 3.3 V ±0.3 V6	8.4 Trademarks10
5.8 Timing Requirements, V <sub>CC</sub> = 5 V ±0.5 V6	8.5 Electrostatic Discharge Caution10
5.9 Switching Characteristics, V <sub>CC</sub> = 2.5 V ±0.2 V6	8.6 Glossary10
5.10 Switching Characteristics, $V_{CC}$ = 3.3 V ±0.3 V6 5.11 Switching Characteristics, $V_{CC}$ = 5 V ±0.5 V6	9 Mechanical, Packaging, and Orderable Information 10

## 3 Revision History

### Changes from Revision B (April 2008) to Revision C (August 2023)

Page

 Added Package Information table, Pin Functions table, ESD Ratings table, Thermal Information table, Device Functional Modes, Device and Documentation Support section, and Mechanical, Packaging, and Orderable Information section

Submit Document Feedback



## **4 Pin Configuration and Functions**

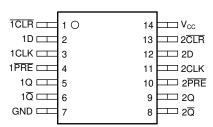


Figure 4-1. D and PW Package 14-Pin SOIC and TSSOP (Top View)

**Table 4-1. Pin Functions** 

PIN		TVDE4	DESCRIPTION
NO.	NAME	TYPE1	DESCRIPTION
1	1 CLR	I	1 clear
2	1D	I	1D input
3	1CLK	I	1 clock
4	1 PRE	I	1 preset
5	1Q	0	1Q output
6	1 Q	0	1 Q output
7	GND	_	GND
8	2 Q	0	2 Q output
9	2Q	0	2Q output
10	2 PRE	I	2 preset
11	2CLK	I	2 clock
12	2D	I	2D input
13	2 CLR	I	2 clear
14	Vcc	_	Supply voltage input

1. Signal Types: I = Input, O = Output, I/O = Input or Output.



## **5 Specifications**

## 5.1 Absolute Maximum Ratings

over operating free-air temperature (unless otherwise noted)(1)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range		-0.5	7	V
VI	Input voltage range <sup>(2)</sup>		-0.5	7	V
Vo	Voltage applied to any output in the h	nigh-impedance or power-off state <sup>(2)</sup>	-0.5	7	V
Vo	Output voltage range <sup>(2) (3)</sup>		-0.5	V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	Input clamp current	V <sub>I</sub> < 0		-20	mA
I <sub>OK</sub>	Output clamp current	V <sub>O</sub> < 0		-50	mA
Io	Continuous output current	V <sub>O</sub> = 0 to V <sub>CC</sub>	-25	25	mA
	Continuous current through V <sub>CC</sub> or GND		-50	50	mA
T <sub>stg</sub>	Storage temperature		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### 5.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic	Human-body model (HBM), per AEC Q100-002 <sup>1</sup>	±2000	V
V <sub>(ESD)</sub>	discharge	Charged device model (CDM), per AEC Q100-011	±1000	'

<sup>(1)</sup> AEC Q100-002 indicates that HBM stressing must be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

#### 5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)<sup>1</sup>

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage		2	5.5	V
		V <sub>CC</sub> = 2 V	1.5		
V	Lligh level input valtage	V <sub>CC</sub> = 2.3 V to 2.7 V	V <sub>CC</sub> x 0.7		V
$V_{IH}$	High-level input voltage	V <sub>CC</sub> = 3 V to 3.6 V	V <sub>CC</sub> x 0.7		V
		V <sub>CC</sub> = 4.5 V to 5.5 V	V <sub>CC</sub> x 0.7		
		V <sub>CC</sub> = 2 V		0.5	
.,	Low level input veltage	V <sub>CC</sub> = 2.3 V to 2.7 V		V <sub>CC</sub> x 0.3	V
V <sub>IL</sub>	Low-level input voltage	V <sub>CC</sub> = 3 V to 3.6 V		V <sub>CC</sub> x 0.3	3 V
		V <sub>CC</sub> = 4.5 V to 5.5 V		V <sub>CC</sub> x 0.3	
VI	Input voltage		0	5.5	V
Vo	Output voltage		0	V <sub>CC</sub>	V
		V <sub>CC</sub> = 2 V		-50	μA
	Lligh level output ourrent	V <sub>CC</sub> = 2.3 V to 2.7 V		-2	
I <sub>OH</sub>	High-level output current	V <sub>CC</sub> = 3 V to 3.6 V		-6	mA
		V <sub>CC</sub> = 4.5 V to 5.5 V		-12	
		V <sub>CC</sub> = 2 V		50	μA
	Low lovel output ourrent	V <sub>CC</sub> = 2.3 V to 2.7 V		2	
I <sub>OL</sub>	Low-level output current	V <sub>CC</sub> = 3 V to 3.6 V		6	mA
		V <sub>CC</sub> = 4.5 V to 5.5 V		12	

Submit Document Feedback

Copyright © 2023 Texas Instruments Incorporated

<sup>(2)</sup> The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>(3)</sup> The value is limited to 5.5-V maximum.

over operating free-air temperature range (unless otherwise noted)<sup>1</sup>

			MIN	MAX	UNIT
		V <sub>CC</sub> = 2.3 V to 2.7 V		200	
Δt/Δν	Input transition rise or fall rate	V <sub>CC</sub> = 3 V to 3.6 V		100	ns/V
		V <sub>CC</sub> = 4.5 V to 5.5 V		20	
T <sub>A</sub>	Operating free-air temperature		-40	125	°C

<sup>(1)</sup> All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. See the TI application report, Implications of Slow or Floating CMOS Inputs, SCBA004.

#### 5.4 Thermal Information

over operating free-air temperature range (unless otherwise noted)

THERMAL METRIC(1)		D	PW	UNIT	
	THERMAL METRIC	14 PINS	14 PINS	UNIT	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	86	113	°C/W	

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

#### 5.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V <sub>cc</sub>	MIN	TYP	MAX	UNIT
		I <sub>OH</sub> = -50 μA	2 to 5.5 V	V <sub>CC</sub> - 0.1			
\ <u>\</u>	High level output voltage	I <sub>OH</sub> = -2 mA	2.3 V	2			V
V <sub>OH</sub>	r ligir level output voltage	I <sub>OH</sub> = -6 mA	3 V	2.48			V
		I <sub>OH</sub> = -12 mA	4.5 V	3.8			
		I <sub>OL</sub> = 50 μA	2 to 5.5 V			0.1	
\ <u>\</u>	Low level output voltage	I <sub>OL</sub> = 2 mA	2.3 V			0.4	V
V <sub>OL</sub>		I <sub>OL</sub> = 6 mA	3 V			0.44	V
		I <sub>OL</sub> = 12 mA	4.5 V			0.55	
I <sub>I</sub>	Input leakage current	V <sub>I</sub> = 5.5 V or GND	0 to 5.5 V			±1	μA
I <sub>CC</sub>	Supply current	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			20	μΑ
I <sub>off</sub>	Input/Output Power-Off Leakage Current	$V_I$ or $V_O = 0$ to 5.5 V	0			5	μΑ
C	Innut Consoitance	V = V or CND	3.3 V		2		pF
Ci	Input Capacitance $V_I = V_{CC}$ or GND		5 V		2		рг

## 5.6 Timing Requirements, $V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$

over recommended operating free-air temperature range,  $V_{CC}$  = 2.5 V ±0.2 V (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

	go travelenio)						
	PARAMETER		T <sub>A</sub> = 25°C		MIN MA	MAX	UNIT
	PARAMETER		MIN	MAX	IVIIIV	IVIAA	UNII
A Dulas duration	PRE or CLR low	8		9		no	
I <sub>W</sub>	Pulse duration	CLK	8		9		ns
	Cation time haters CLIVA	Data	8		9		
t <sub>su</sub>	Setup time before CLK↑	PRE or CLR low	7		7		ns
t <sub>h</sub>	Hold time, data after CLK↑		0.5		0.5		ns

### 5.7 Timing Requirements, $V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$

over recommended operating free-air temperature range,  $V_{CC}$  = 3.3 V ±0.3 V (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

	DADAMETED		T <sub>A</sub> = 25°C		T <sub>A</sub> = 25°C		MIN	MAX	UNIT
	PARAMETER		MIN	MAX	IVIIIN	IVIAA	UNIT		
t <sub>w</sub> Pulse duration	PRE or CLR low	6		7		no			
	Pulse duration	CLK	6		7		ns		
	Setup time before CLK↑	Data	6		7				
t <sub>su</sub>		PRE or CLR low	5		5		ns		
t <sub>h</sub>	Hold time, data after CLK↑		0.5		0.5		ns		

## 5.8 Timing Requirements, $V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$

over recommended operating free-air temperature range,  $V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$  (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

	DADAMETED		T <sub>A</sub> = 25°C		MIN	MAX	UNIT
	PARAMETER	PARAMETER		MAX	IVIIIN	IVIAA	UNII
t <sub>w</sub> Pulse duration	PRE or CLR low	5		5		no	
	Pulse duration	CLK	5		5		ns
	Setup time before CLK↑	Data	5		5	_	no
t <sub>su</sub>	Setup time before CLK	PRE or CLR low	3		3		ns
t <sub>h</sub>	Hold time, data after CLK↑		0.5		0.5		ns

### 5.9 Switching Characteristics, V<sub>CC</sub> = 2.5 V ±0.2 V

over recommended operating free-air temperature range,  $V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$  (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

			1040	т	_ = 25°C					
PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD	1 <sub>A</sub> - 23 0			MIN	MAX	UNIT	
	,	, ,	CAPACITANCE	MIN	TYP	MAX				
f <sub>max</sub>			C <sub>L</sub> = 50 pF	30	70		25		MH <sub>Z</sub>	
+	PRE or CLR	Q or Q	C <sub>1</sub> = 50 pF		13	17.4	1	20	ns	
<sup>l</sup> pd	CLK	Q or Q	CL = 50 PF		14.2	20	1	23		

#### 5.10 Switching Characteristics, $V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$

over recommended operating free-air temperature range,  $V_{CC}$  = 3.3 V ±0.3 V (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD	T,	= 25°C		MIN	MAX	UNIT	
FARAMETER	PROW (INFOT)	10 (0011-01)	CAPACITANCE	MIN	TYP	MAX	IVIIIA	WAX		
f <sub>max</sub>			C <sub>L</sub> = 50 pF	50	90		45		MH <sub>Z</sub>	
	PRE or CLR	$Q \text{ or } \overline{Q}$ $C_1 = 50 \text{ pF}$		9.2	15.8	1	18	no		
CLF	CLK	QuiQ	CL = 50 PF		10.2	15.4	1	18	ns	

### 5.11 Switching Characteristics, $V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$

over recommended operating free-air temperature range,  $V_{CC}$  = 5 V ±0.5 V (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD	T	√ = 25°C		MIN	MAX	UNIT	
PARAMETER	PROW (INPOT)	10 (001701)	CAPACITANCE	MIN	TYP	MAX	IVIIIN		UNIT	
f <sub>max</sub>			C <sub>L</sub> = 50 pF	90	140		75		MHZ	
+	PRE or CLR	Q or $\overline{\mathbb{Q}}$	C <sub>L</sub> = 50 pF		6.6	9.7	1	12	no	
<sup>T</sup> pd	CLK	QuiQ	CL = 50 pr		7.2	9.3	1	13	ns	

### **5.12 Noise Characteristics**

 $V_{CC} = 3.3 \text{ V}, C_L = 50 \text{ pF}, T_A = 25^{\circ}\text{C}^{(1)}$ 

	PARAMETER	MIN	TYP	MAX	UNIT
V <sub>OL(P)</sub>	Quiet output, maximum dynamic V <sub>OL</sub>		0.1	0.8	
V <sub>OL(V)</sub>	Quiet output, minimum dynamic V <sub>OL</sub>		0	-0.8	
V <sub>OH(V)</sub>	Quiet output, minimum dynamic V <sub>OH</sub>		3.2		V
V <sub>IH(D)</sub>	High-level dynamic input voltage	2.31			
$V_{IL(D)}$	Low-level dynamic input voltage			0.99	

<sup>(1)</sup> Characteristics are for surface-mount packages only.

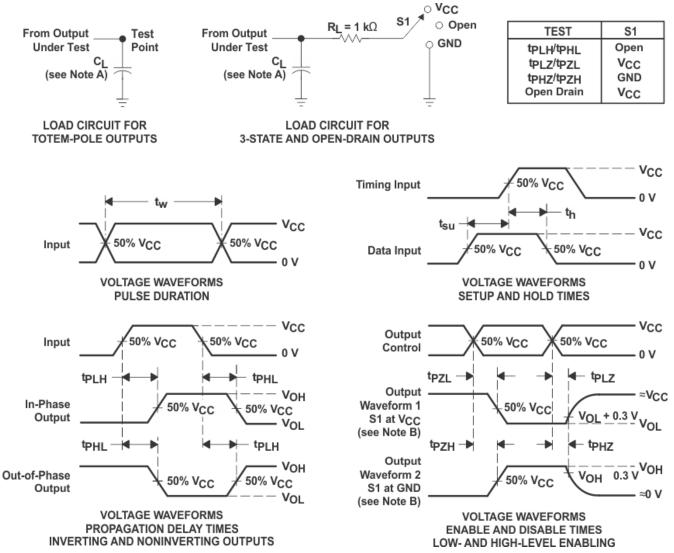
## **5.13 Operating Characteristics**

 $T_A = 25^{\circ}C$ 

PARAMETER	TEST CONDITIONS	V <sub>cc</sub>	TYP	UNIT
C <sub>nd</sub> Power dissipation capacitance	C <sub>1</sub> = 50 pF, f = 10 MHz	3.3 V	21	pF
C <sub>pd</sub> Fower dissipation capacitance	C <sub>L</sub> = 50 pr, f = 10 MHZ	3.3 V 21	рг	



#### **6 Parameter Measurement Information**



- A. C<sub>I</sub> includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_f \leq 3$  ns.  $t_f \leq 3$  ns.
- D. The outputs are measured one at a time, with one input transition per measurement.
- E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
- F.  $t_{PZL}$  and tPZH are the same as  $t_{en}$ .
- G.  $t_{PHL}$  and  $t_{PLH}$  are the same as  $t_{pd}$ .
- H. All parameters and waveforms are not applicable to all devices.

Figure 6-1. Load Circuit and Voltage Waveforms

### 7 Detailed Description

#### 7.1 Overview

This dual positive-edge-triggered D-type flip-flop is designed for 2-V to 5.5-V V<sub>CC</sub> operation.

A low level at the preset  $(\overline{PRE})$  or clear  $(\overline{CLR})$  inputs sets or resets the outputs, regardless of the levels of the other inputs. When  $\overline{PRE}$  and  $\overline{CLR}$  are inactive (high), data at the data (D) inputs meeting the setup-time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold-time interval, data at the D input can be changed without affecting the levels at the outputs.

This device is fully specified for partial-power-down applications using  $I_{\text{off}}$ . The  $I_{\text{off}}$  circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

#### 7.2 Functional Block Diagram

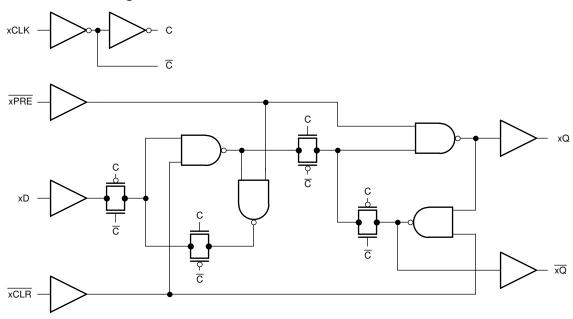


Figure 7-1. Logic Diagram, Each Flip-flop (Positive Logic)

#### 7.3 Device Functional Modes

**Table 7-1. Function Table** 

	INPUT	OUTPU	TS <sup>(2)</sup>		
PRE	CLR	CLK	D	Q	Q
L	Н	Х	Х	Н	L
Н	L	X	Χ	L	Н
L	L	X	X	H <sup>(3)</sup>	H <sup>(3)</sup>
Н	Н	<b>↑</b>	Н	Н	L
Н	Н	<b>↑</b>	L	L	Н
Н	Н	L	X	$Q_0$	$\overline{Q}_0$

- (1) H = High Voltage Level, L = Low Voltage Level, X = Don't Care
- (2) H = Driving High, L = Driving Low, Z = High Impedance State
- (3) This configuration is nonstable; that is, it does not persist when PRE or CLR returns to its inactive (high) level.

### 8 Device and Documentation Support

#### 8.1 Documentation Support

#### 8.1.1 Related Documentation

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

Table 8-1. Related Links

F	PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
SN74	4LV74A-Q1	Click here	Click here	Click here	Click here	Click here

## 8.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### 8.3 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 8.4 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

### 8.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 8.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

## 9 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Submit Document Feedback

www.ti.com 18-Jul-2023

#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
SN74LV74AQDRG4Q1	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LV74A	Samples
SN74LV74AQDRQ1	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LV74A	Samples
SN74LV74AQPWRG4Q1	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LV74A	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

**Important Information and Disclaimer:** The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

## PACKAGE OPTION ADDENDUM

www.ti.com 18-Jul-2023

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF SN74LV74A-Q1:

Catalog : SN74LV74A

■ Enhanced Product : SN74LV74A-EP

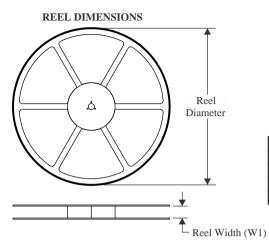
NOTE: Qualified Version Definitions:

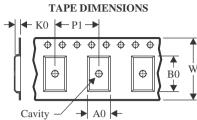
- Catalog TI's standard catalog product
- Enhanced Product Supports Defense, Aerospace and Medical Applications

## **PACKAGE MATERIALS INFORMATION**

www.ti.com 18-Jul-2023

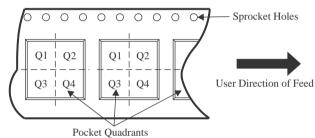
#### TAPE AND REEL INFORMATION





	<u> </u>
A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

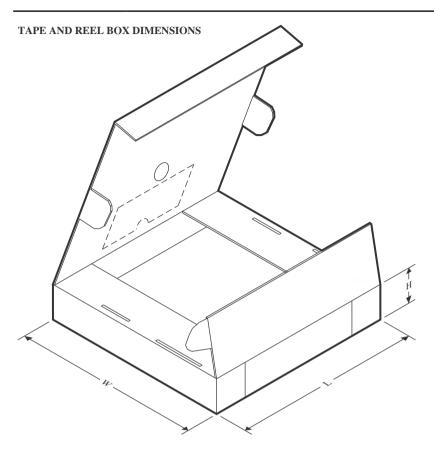


#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74LV74AQPWRG4Q1	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

## **PACKAGE MATERIALS INFORMATION**

www.ti.com 18-Jul-2023

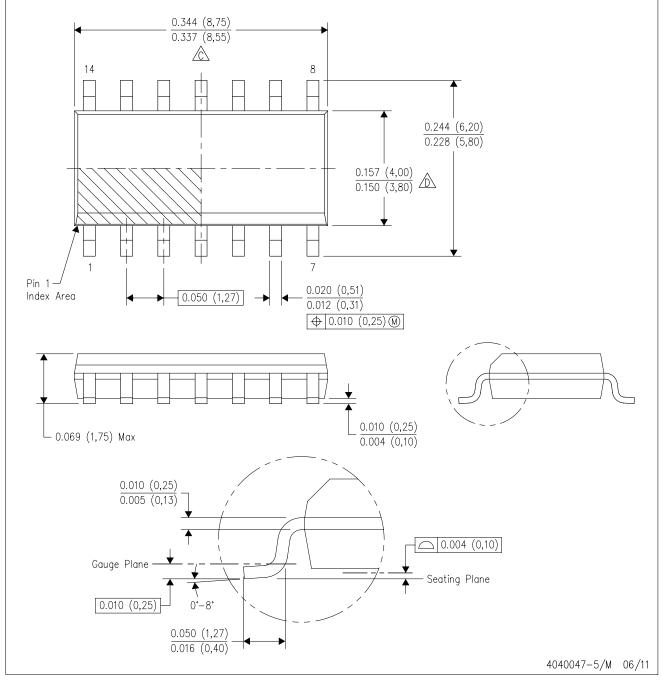


#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74LV74AQPWRG4Q1	TSSOP	PW	14	2000	356.0	356.0	35.0

## D (R-PDSO-G14)

### PLASTIC SMALL OUTLINE



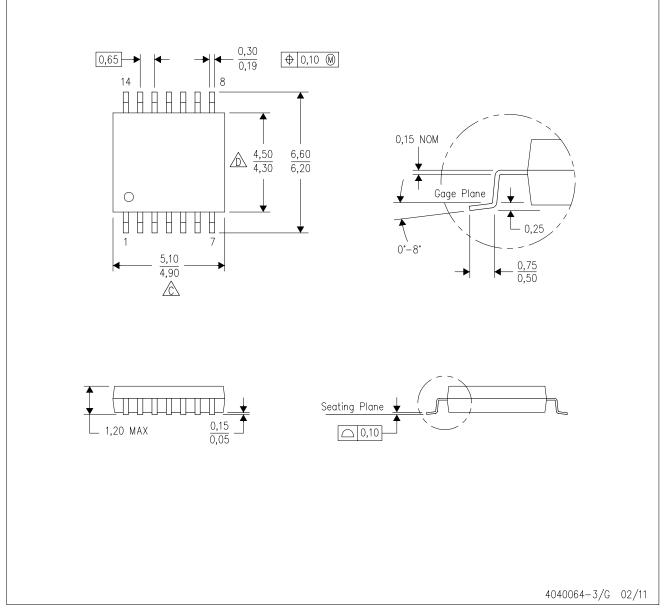
NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AB.



PW (R-PDSO-G14)

## PLASTIC SMALL OUTLINE



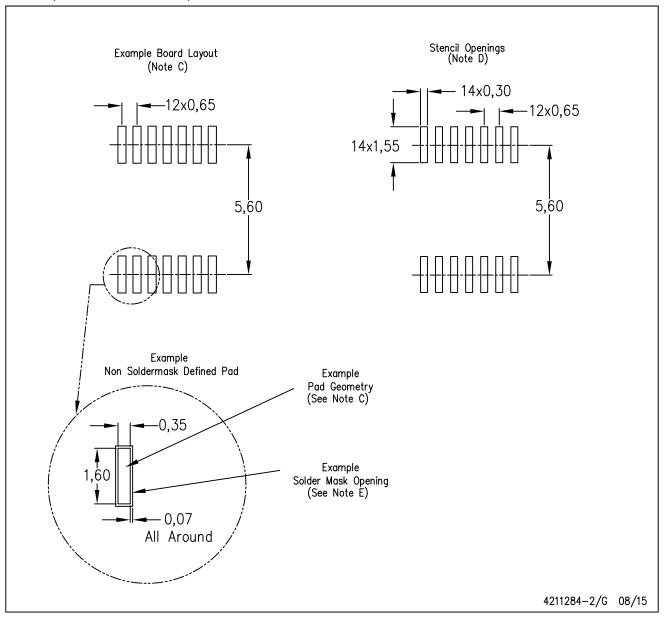
NOTES:

- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



# PW (R-PDSO-G14)

## PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



#### IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2023, Texas Instruments Incorporated